

Search Notes

Application/Control No.

10/644,794

Examiner

Emily Y. Chan

Applicant(s)/Patent under
Reexamination

NOJIRI ET AL.

Art Unit

2829

SEARCHED

Class	Subclass	Date	Examiner
324	770	5/9/2005	EC
324	750-765	5/9/2005	EC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship and EAST for all databases searched.	5/9/2005	EC
Consulted with primary examiner Vinh P Nguyen.	5/9/2005	EC